Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	r
10/646,791	ELIYAHU ET AL.	
Examiner	Art Unit	
Chapman E. Jeanette	3635	

SEARCHED								
Class	Subclass	Date		Examiner				
<b>52</b>	266, 231, 281, 286	7/4105		7/4105		7/4105		JC
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Application No.	Applicant(s)	
10/646,791	ELIYAHU ET AL.	
Examiner	Art Unit	
Chapman E Jeanette	3635	

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Class		Subclass		Date	Examiner	
52		238.1,266, 271,281,2 86,309.9	9/2	6/2004	JC	
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